

Front end Hybrid Industrial Tester

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<http://www.fynu.ucl.ac.be/themes/he/cms/activities/tracker/hybrids.html>

LHC project

Introduction

Large Hadron Collider

Before LHC : LEP

new physics at 1 TeV scale ?

LHC performance

pp collider (7-on-7 TeV)

high luminosity : up to $10^{34} \text{ cm}^{-2}\text{s}^{-1}$

bunch crossing every 25 ns

LHC design

superconducting magnets : 8 T to bend the beams

1.9K superfluid helium cooling bath

CMS, LHCb, Alice, Atlas experiments



LHC project

CMS experiment

Compact Muon Solenoid

General purpose detector

Searches for Higgs boson...

Biggest magnet ever built

$B \sim 4 T, R \sim 3.4 m, L \sim 12.5 m$

CMS structure

tracker

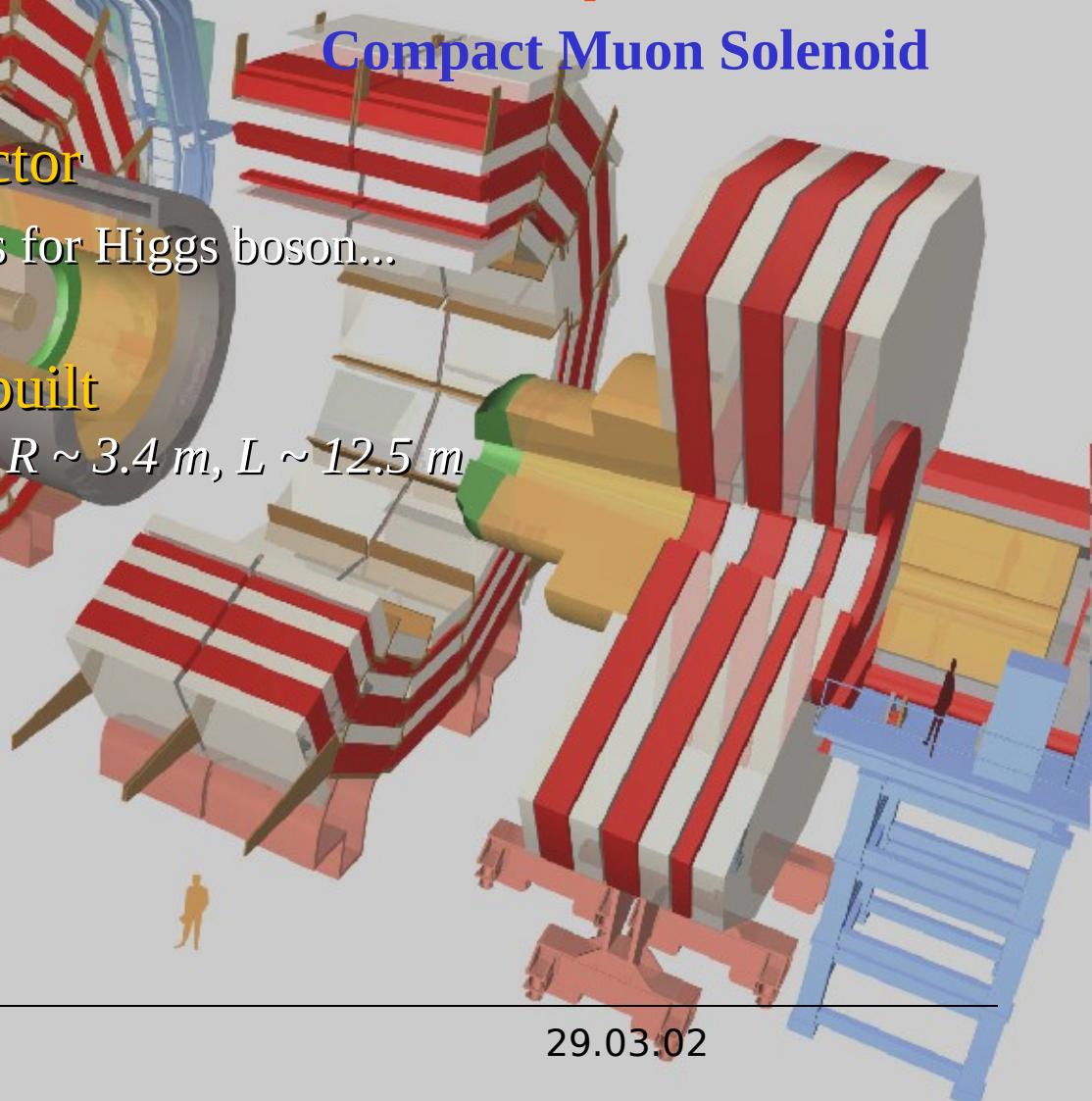
electromagnetic calorimeter

hadronic calorimeter

solenoid

magnet yoke

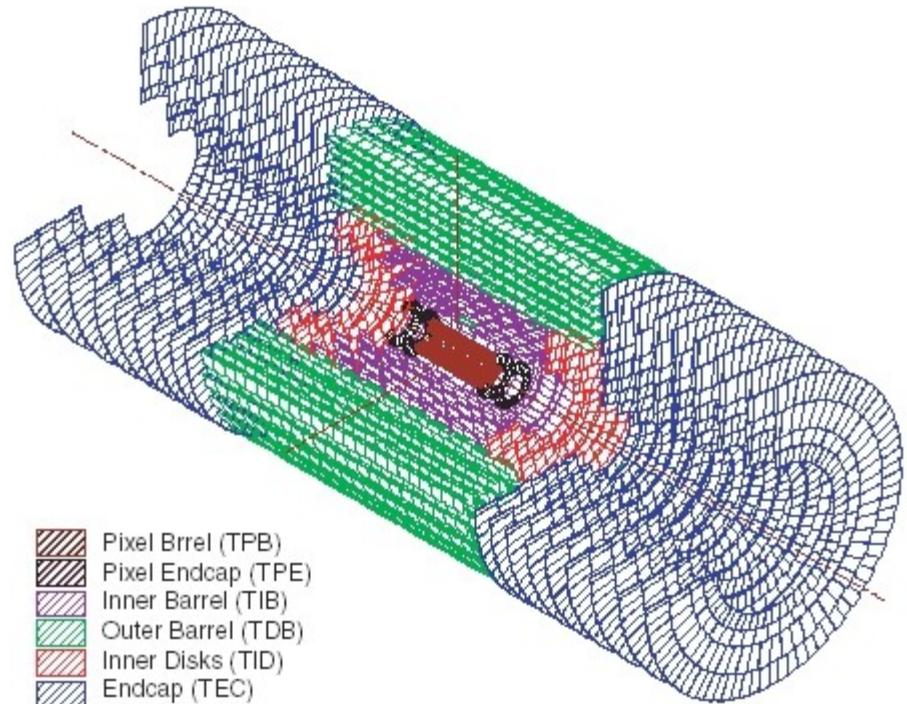
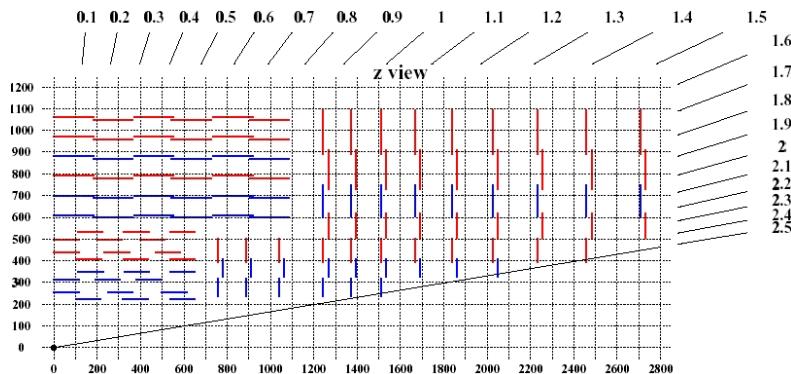
μ chambers



Disposition

- détecteurs à pixels → 5×10^7 canaux
- senseurs Si : $\sim 223 \text{ m}^2$ → 10^7 strips → 78 000 APVs

couches mono ou stéréo

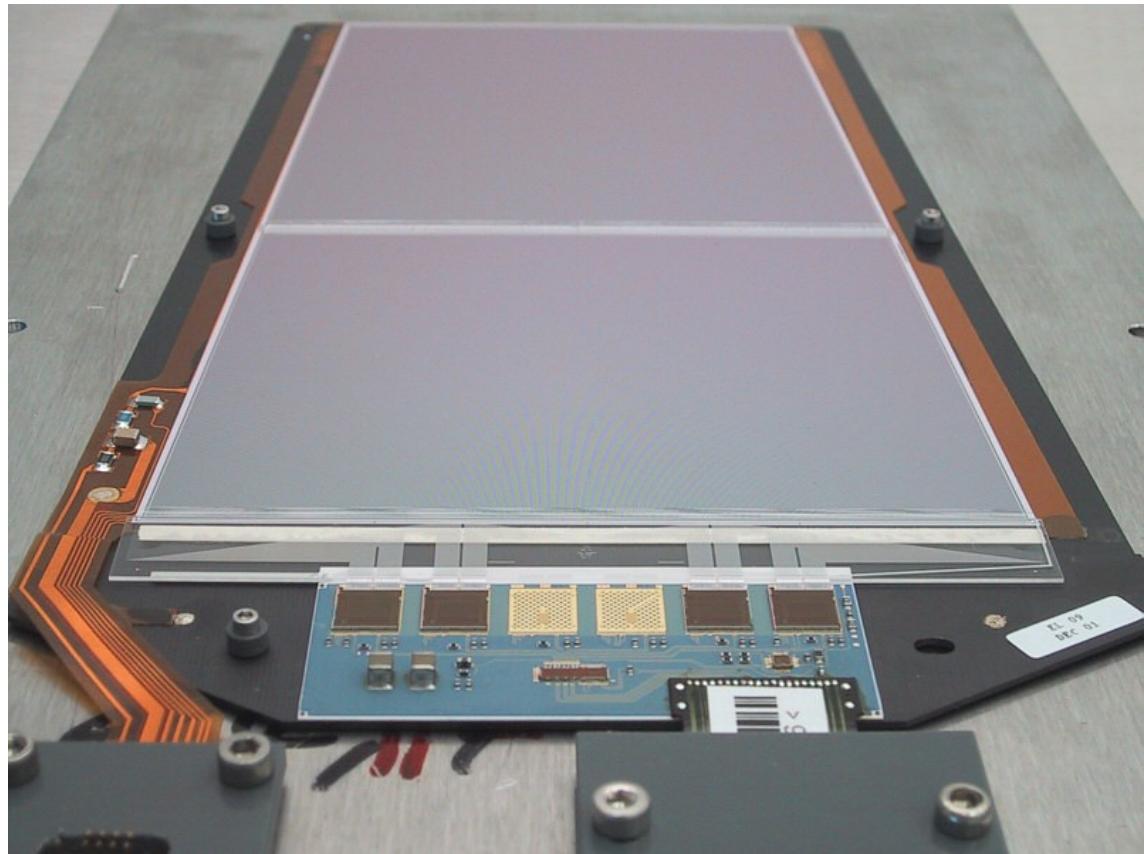


cylindres / disques

- Pixel Brrel (TPB)
- Pixel Endcap (TPE)
- Inner Barrel (TIB)
- Outer Barrel (TDB)
- Inner Disks (TID)
- Endcap (TEC)

Eléments : modules

Module



FEH

pitch adapter

senseurs Si (2 en *daisy-chain*)

structure en fibre de carbone → sur circuit de refroidissement

CMS Tracker

Hybrids

What *listens* to the detector :

read-out electronics for silicon sensors

APV25

These chips need:

clock and trigger distribution

data transmission (multiplexing)

current/ temperature control

PLL

MUX

DCU

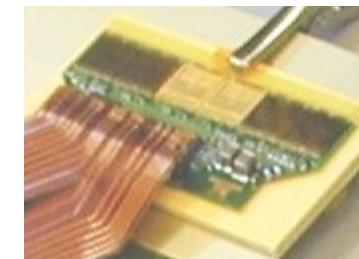
Front end Hybrid Industrial Tester

Three complementary tests of different natures :

Connectivity Test (CT)

Electrical Test (ET)

Functional Test (FT)



mono-FHIT



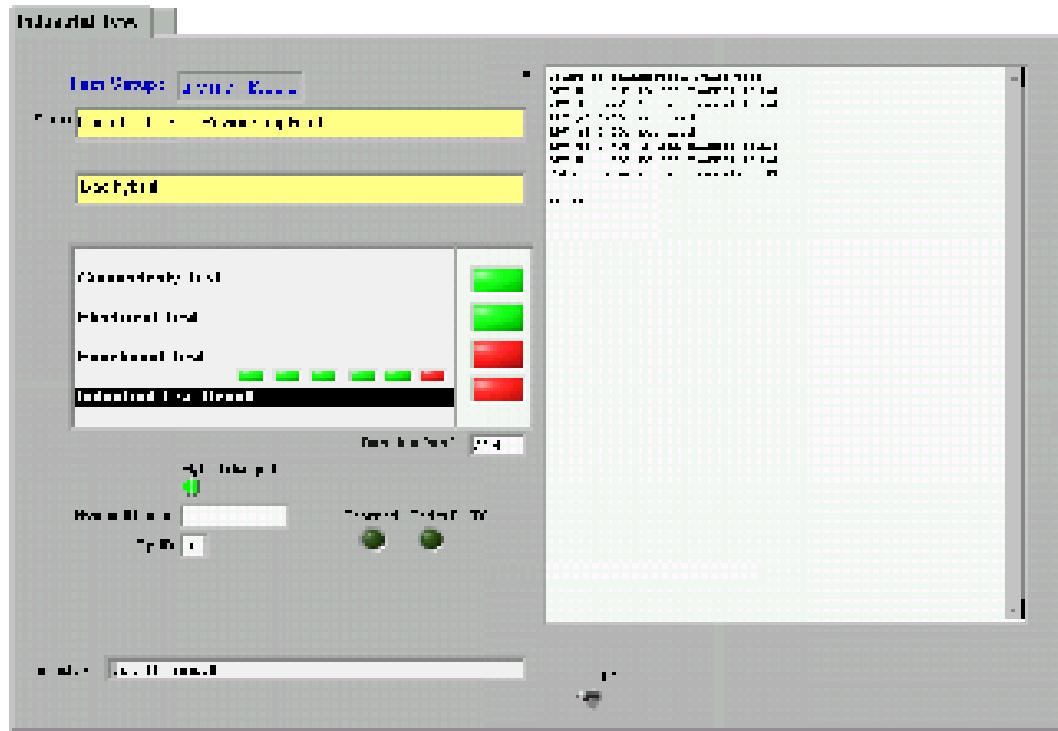
power supply

dual-FHIT



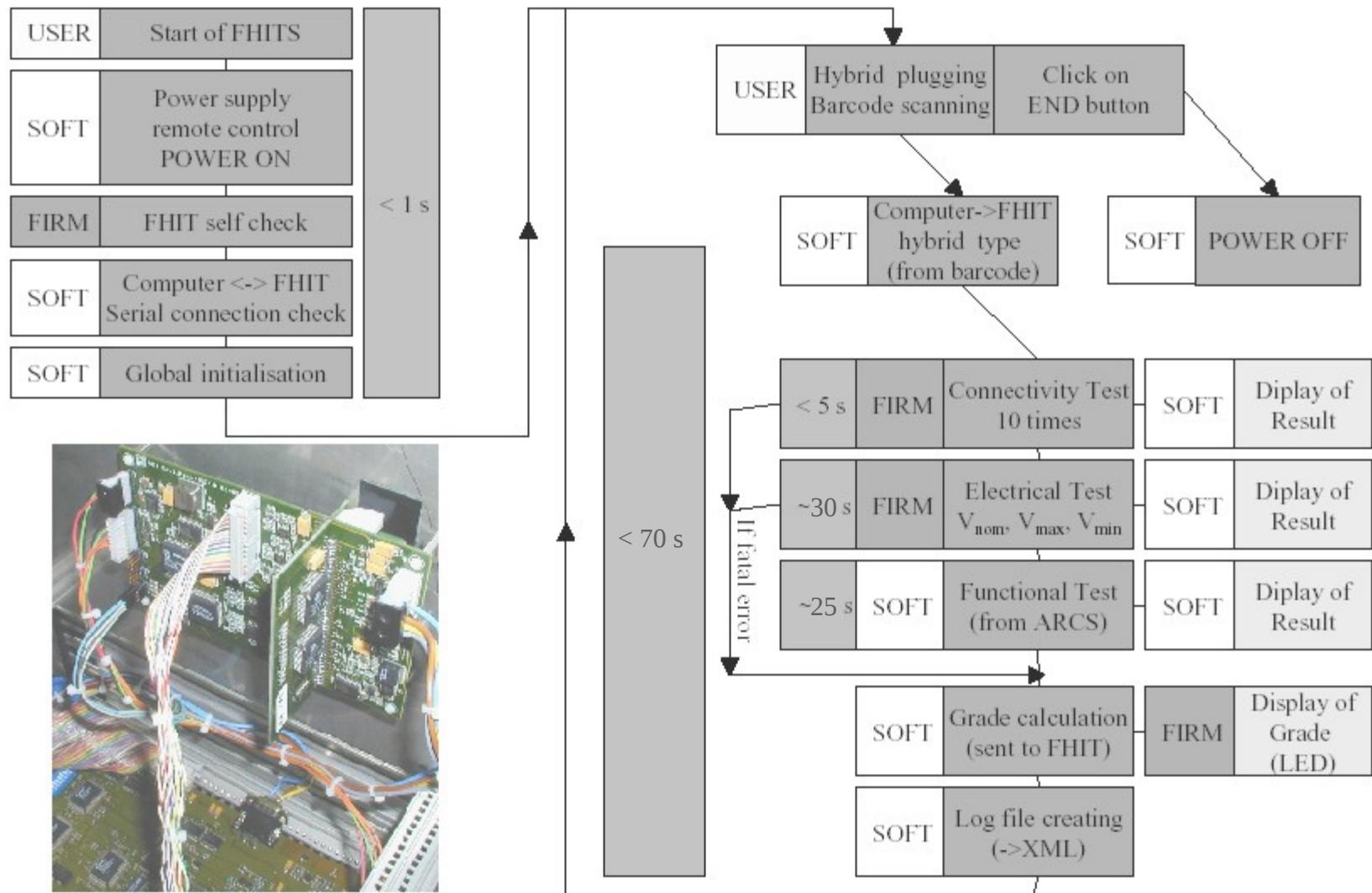
FHIT software

- test sequence, results and detected errors
- power supply control
- barcode scanning



LabVIEW interface

Block diagram



Analysis

Data acquisition

data acquisition in real (industrial like) conditions

62 FEH tested in Strasbourg

and 51 FEH passed CT and ET successfully

FEH types : 1663, 1664, 1665 = TOB/TEC top-4, bot-4, top-6

FHIT setup proved to be reliable

rapidity : dual-FHIT used

test ~ 70 seconds > time needed to handle FEH

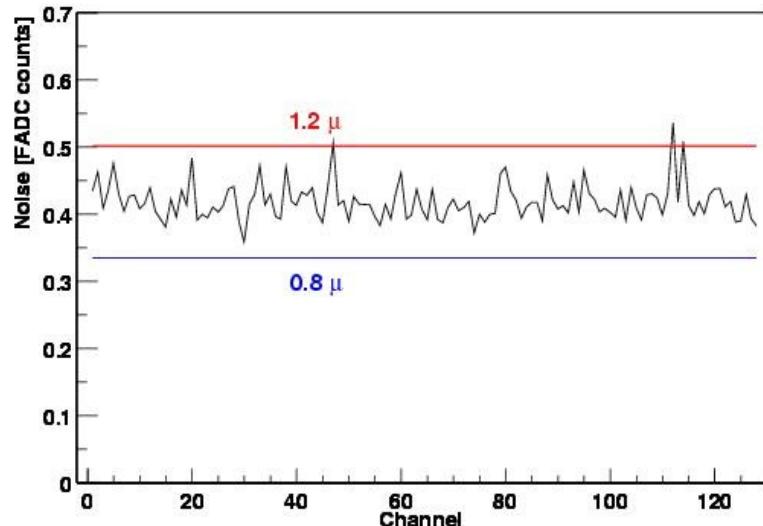
analysis :

APV25s currents, DCU calibration, APVMUX resistors, pedestal, noise and gain measurements.

Analysis

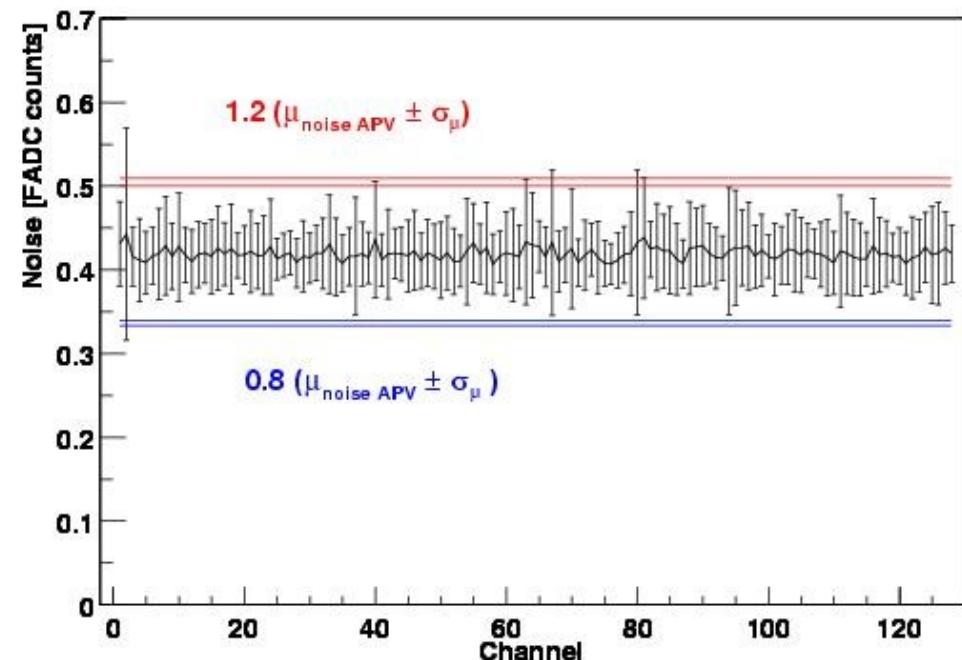
Data analysis : noise (FT)

Noise distribution per channel (APV = 0x20, Part = 1665, N = 1)



noise per channel for an APV of one FEH
good/bad channels selection criterion :
 $0.8 \mu < N_i < 1.2 \mu$

Noise distribution per channel (APV = 0x20, Part = 1663, N = 38)



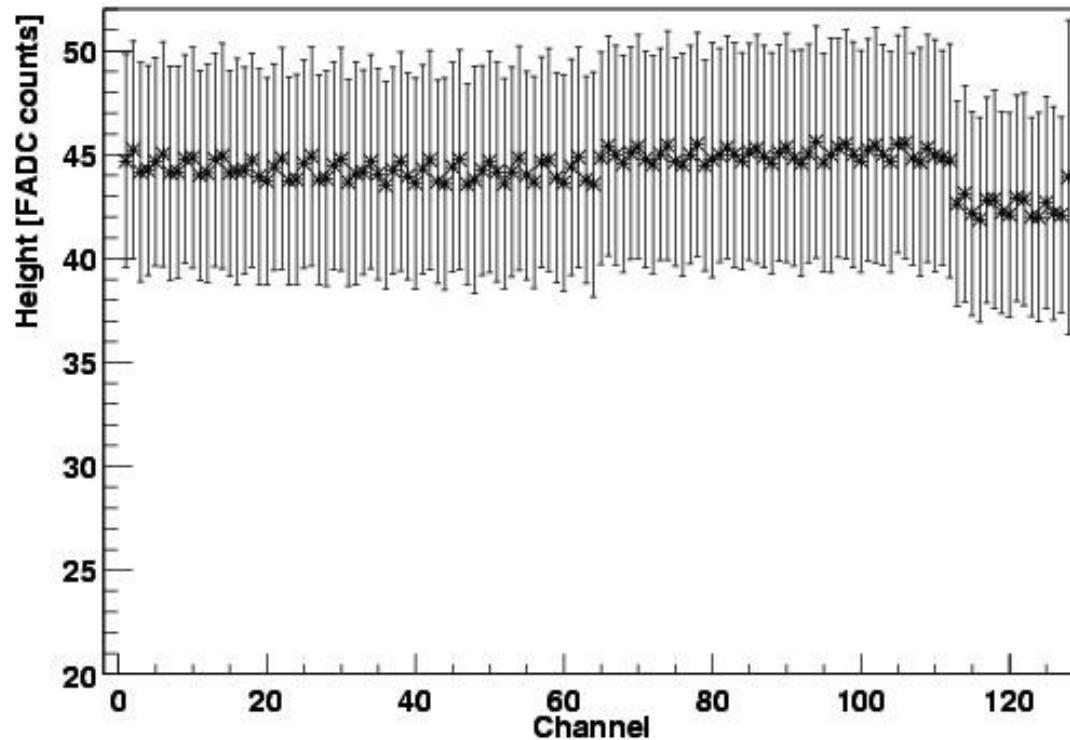
distribution of noise per
channel for an APV address and for
the sample of a given FEH type

criterion too restrictive !

Analysis

Data analysis : gain (FT)

Distribution of response to calibration pulse per channel (APV = 0x21, Part = 1663, N = 38)



visible structures :
- 3 thresholds
- groups of 4
channels

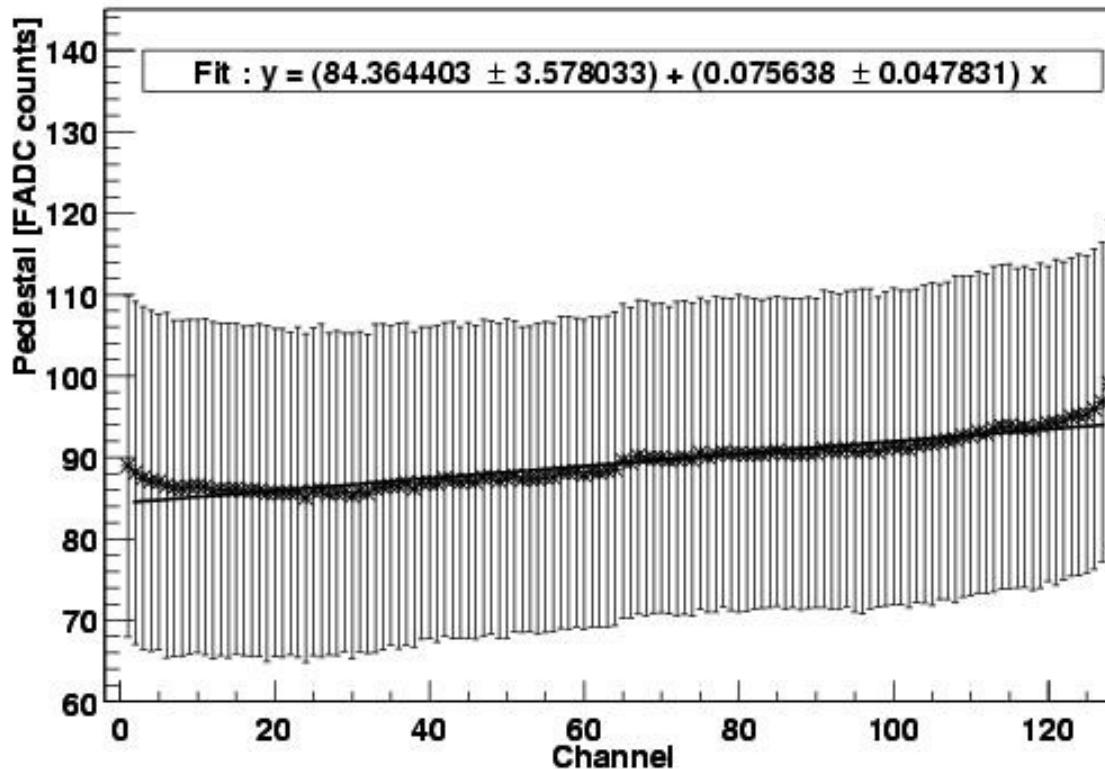
channels NOT in order

gain distribution per channel for an APV address and the sample of a given FEH type

Analysis

Data analysis : pedestal (FT)

Pedestal distribution per channel (APV = 0x21, Part = 1663, N = 38)



Pedestal distribution per channel for an APV address and for the sample of a given FEH type

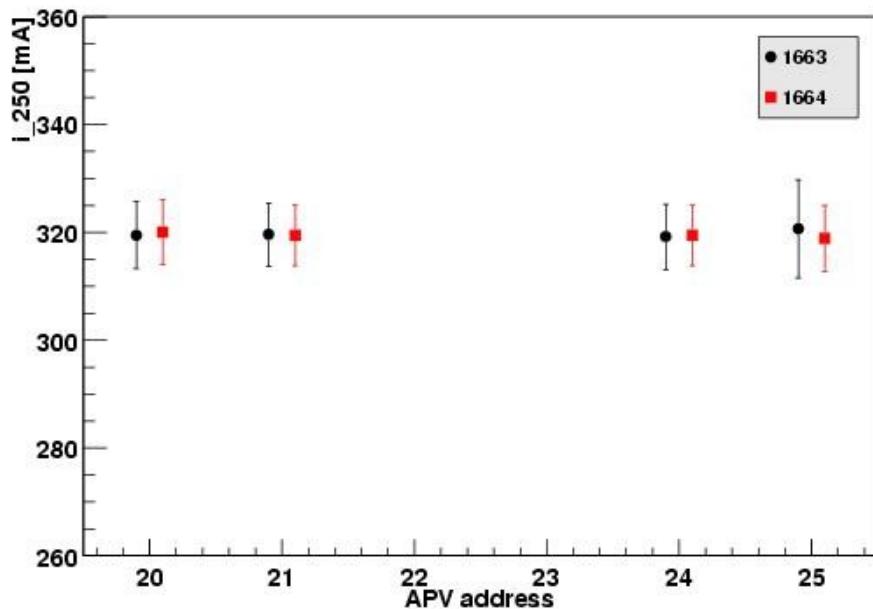
visible structures
:
- linear increase
- border effects

*for each FEH :
strong
correlation
between
channels*

Analysis

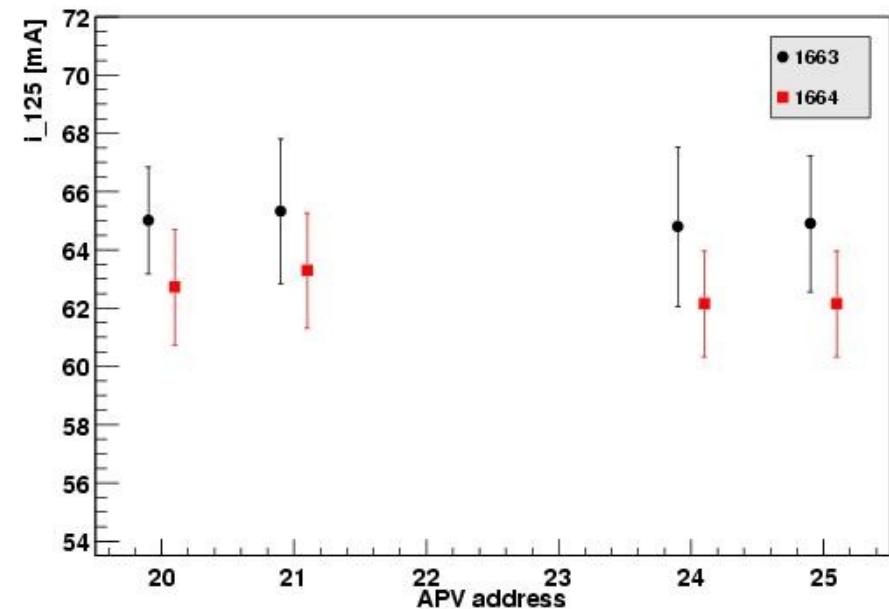
Data analysis : currents (ET)

1 σ current distribution per APV and FEH type (V_{nom})



I_{250}

1 σ current distribution per APV and FEH type (V_{nom})



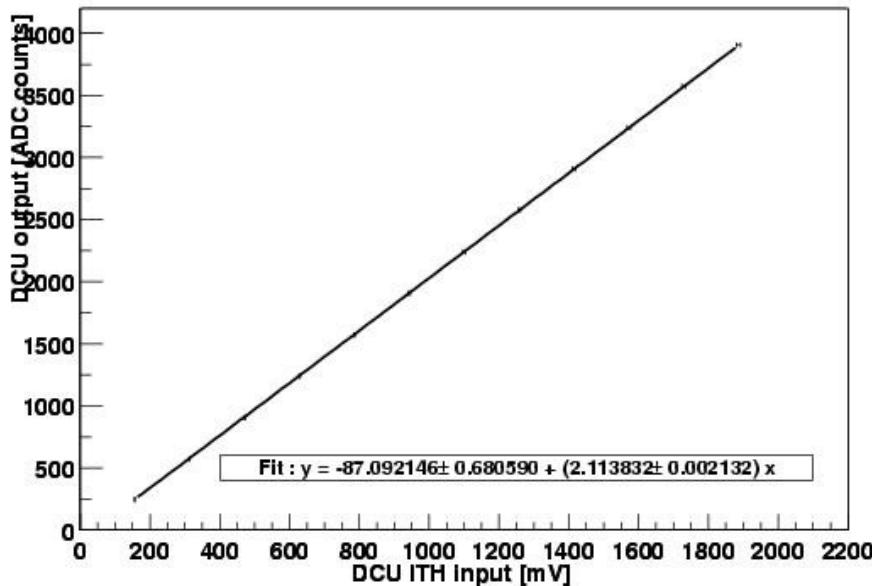
I_{125}

APV current consumption
distribution for an APV address and a
sample of a given FEH type

Analysis

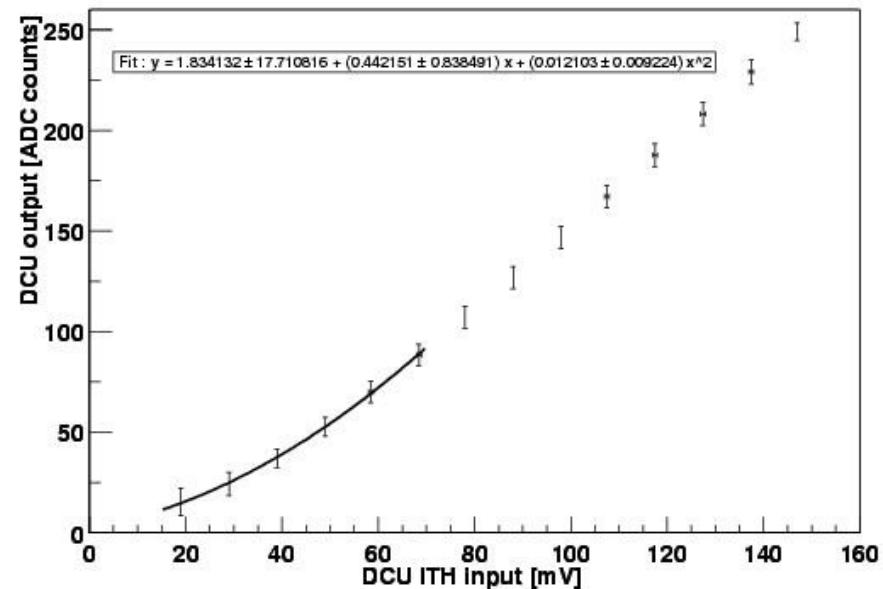
Data analysis : DCU (ET)

DCU calibration for FEH 1665 (V_{nom}, N= 1)



linear and non-linear regions

DCU calibration for FEH 1663 (V_{nom}, N= 38)



DCU calibration for an APV
address
and a given FEH

Conclusions

FHIT & FHITS : realised and tested

data acquisition in *industrial* conditions

first data analysis : characterization of hybrids

FHIT quick reference guide available

<http://www.fynu.ucl.ac.be/themes/he/cms/activities/tracker/hybrids.html>